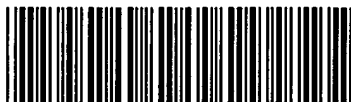


Search Notes

Application/Control No.

10/609,017

Examiner

Dah-Wei D. Yuan

Applicant(s)/Patent under
Reexamination

MARKOSKI ET AL.

Art Unit

1745

SEARCHED

Class	Subclass	Date	Examiner
429	12	2/15/2006	DWY
429	17	2/15/2006	DWY
429	18	2/15/2006	DWY
429	38	2/15/2006	DWY

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	2/15/2006	DWY
STN	2/15/2006	DWY